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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	(inspect\$3 and substrat\$3 and defect\$1 and light\$3 and beam\$1 and scatter\$3 and compar\$3 and intensit\$3 and maximum and value\$1).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/01 10:14
L2	0	356/237.100.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/01 10:14
L3	2407	356/237.1.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/01 10:14
L4	0	(inspect\$3 and substrat\$3 and defect\$1 and light\$3 and beam\$1 and scatter\$3 and compar\$3 and intensit\$3 and maximum and value\$1).clm. and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/01 10:14

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